

Search Notes

Application/Control No.

10/614,056

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

ANDO, TAKESHI

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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